

MaxEye.Basic Series

OPTICAL FLAW SURFACE INSPECTION SYSTEM

Enhanced detectabilities with easy operation
Entry model machine based on
experienced technology enabled efficient
optimization for applications.

■ Fully digitalized

Originally designed camera and digital transmission technology enables to lengthen the distance between camera and SPU up to 50m with immunity to noises and statics in production line environment.

■ Defect judgement

MaxEye.Basic can select best suited defect judgement system from cost, function and performance perspective. MaxEye. Basic/40C · 80C categorizes defects up to 120 kinds by means of the characteristic quantities. MaxEye. Basic/40 · 80 can judge defects by means of the defect width(mm), length(mm) and area(mm²). Detection circuitry such as video, differential, streak, contamination can be allocated flexibly to 12 circuitries for judgement. This flexibility enables making up precise inspecting conditions.

■ Priority judgement

Defects are classified on a scale of 1 to 10 according to priority. By setting the trigger level, such as the external output and the alarm, on the defect level, the system can be used as a tool for quality control as well as production control.

■ Repeating defect/Cluster defect

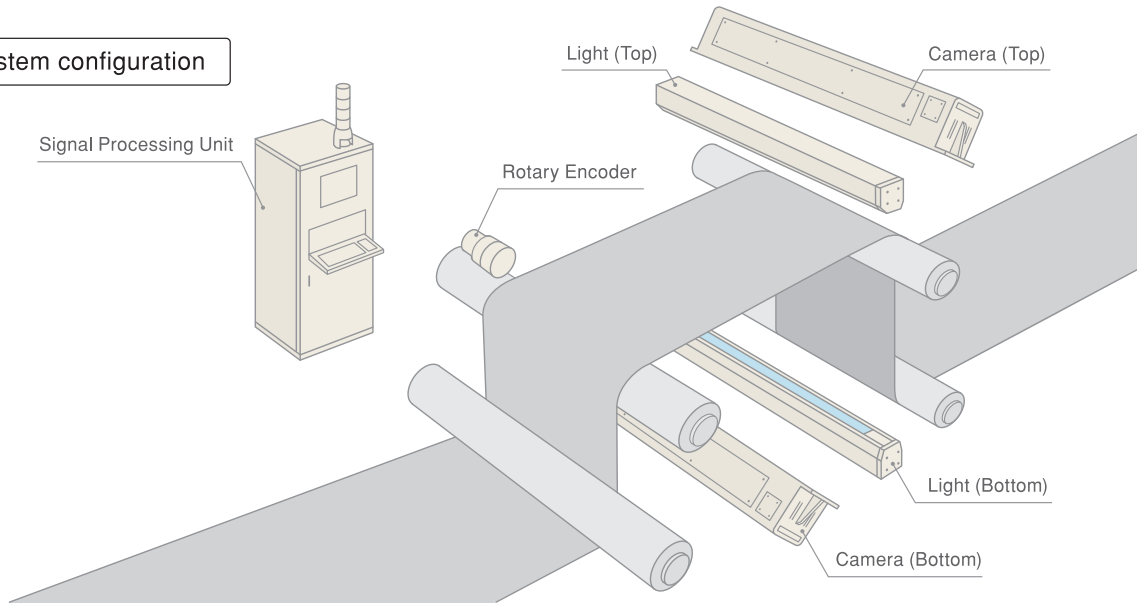
The source of defects can be analyzed effectively by detecting repeating defects or clustered defects. For this feature, the system can be utilized not merely to prevent failure products but also to produce only quality tools.

■ Reliable inspection system

Reliable and easy-maintenance system is realized by adopting the built-in board computer and fault-tolerance hard disk.



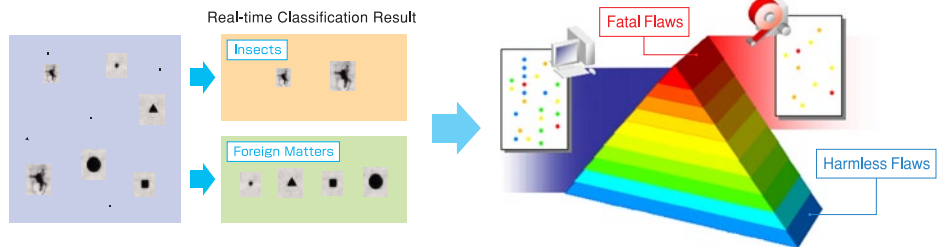
System configuration



Defect classification / Priority judgement

Applicable line

- Film ● Paper
- Non-woven fabric
- Metal ● Coated film etc.



Camera lineup

Model	Pixels	Data Rate (MHz)	Pixel size (μm)	Characteristics
SCHMx	2000	40	7×7	Standard model best fit for optical flaw inspection for web.
	4000			
PCHMx (High Sensitivity Camera)	2000	80	14×14	Low Contrast and minute flaws detectable by High Sensitivity Model
	4000			

SPEC

		MaxEye.Basic/40	MaxEye.Basic/80	MaxEye.Basic/40C	MaxEye.Basic/80C
Camera		2000pix,4000pix/40MHz	2000pix,4000pix/80MHz	2000pix,4000pix/40MHz	2000pix,4000pix/80MHz
Light source		LED line illumination, Halogen lamp, Metal halide lamp, Fluorescent lamp			
Detection Circuit		4 Circuits (Bright and dark thresholds for each circuit.)			
Defect Judgemnet		Discrimination by defect width, length, area (12 types)		Classification by the characteristic quantities (120 types)	
		Repeating defect, Density defect			
Defect image * In the case of 256×256	Storage	Maximum 60,000pcs/lot * Storing lot number may be changed by defect occurrence.			
	Transfer capability	300 images / sec. * In the case that Server function is separated.			
	Buffer	512 images / Cam			
Accessory function		Wave monitor, Assurance function of basic detection, Multilanguage-ready, Self Diagnostic function, HTML output, CSV output, (Setting assist function, Rejudgement function *MaxEye.Basic/40C,80C only)			



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